

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Serial No.:	10/701,332	)	
		)	
Filed:	November 4, 2003	)	Conf. No.: 5874
		)	
Title:	<b>A Novel BISR Mode to Test</b>	)	
	<b>the Redundant Elements and</b>	)	
	<b>Regular Functional Memory</b>	)	
	<b>to Avoid Test Escapes</b>	)	
		)	
Inventor:	Ghasi R. Agrawal et al.	)	
		)	
Art Unit:	2117	)	
		)	
Examiner:	Steve N. Nguyen	)	
		)	
Atty. Ref:	03-1343	)	

**RESPONSE TO THE OFFICE ACTION MAILED OCTOBER 26, 2009**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed October 26, 2009, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.